

150V N-Channel Enhancement Mode MOSFET

Description

The AP260N15P/T uses advanced **APM-SGT_r** technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 10V. This device is suitable for use as a Battery protection or in other Switching application.

General Features

$V_{DS} = 150V$ $I_D = 260A$

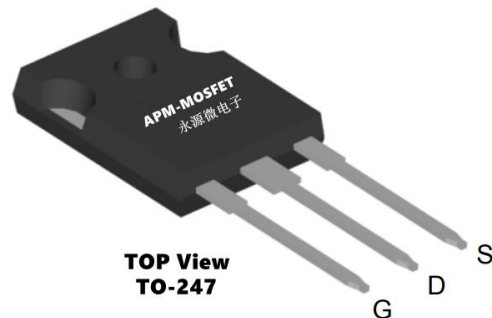
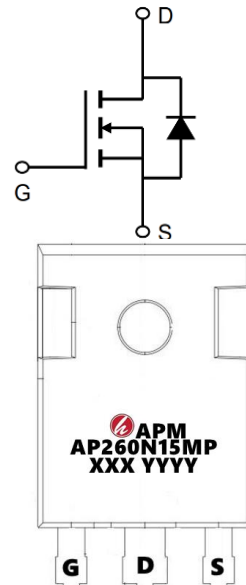
$R_{DS(ON)} < 5.8m\Omega$ @ $V_{GS}=10V$ (Type: **4.8mΩ**)

Application

DC/DC Converter

LED Backlighting

Power Management Switches



Package Marking and Ordering Information

| Product ID | Pack | Marking | Qty(PCS) |
|------------|-----------|---------------------|----------|
| AP260N15P | TO-247-3L | AP260N15MP XXX YYYY | 1000 |

Absolute Maximum Ratings ($T_C=25^\circ\text{C}$ unless otherwise noted)

| Symbol | Parameter | Rating | Units |
|-----------------------------|------------------------------------------|------------|--------------------|
| V_{DS} | Drain-Source Voltage | 150 | V |
| V_{GS} | Gate-Source Voltage | ± 20 | V |
| $I_D@T_C=25^\circ\text{C}$ | Continuous Drain Current, V_{GS} @ 10V | 260 | A |
| $I_D@T_C=100^\circ\text{C}$ | Continuous Drain Current, V_{GS} @ 10V | 185 | A |
| IDM | Pulsed Drain Current | 720 | A |
| EAS | Single Pulse Avalanche Energy | 1764 | mJ |
| IAS | Avalanche Current | 64 | A |
| $P_D@T_C=25^\circ\text{C}$ | Total Power Dissipation ⁴ | 326 | W |
| TSTG | Storage Temperature Range | -55 to 150 | $^\circ\text{C}$ |
| T_J | Operating Junction Temperature Range | -55 to 150 | $^\circ\text{C}$ |
| $R_{\theta JA}$ | Thermal Resistance Junction-Ambient | 0.46 | $^\circ\text{C/W}$ |
| $R_{\theta JC}$ | Thermal Resistance Junction-Case | 62 | $^\circ\text{C/W}$ |

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Electrical Characteristics (T_c=25°C unless otherwise noted)

| Symbol | Parameter | Conditions | Min | Typ | Max | Unit |
|---------|-----------------------------------|------------------------------------------------------------------|-----|-------|------|------|
| BVDSS | Drain-Source Breakdown Voltage | V _{GS} =0V ID=250μA | 150 | 165 | | V |
| IDSS | Zero Gate Voltage Drain Current | V _{DS} =140V, V _{GS} =0V | | | 1 | μA |
| IGSS | Gate-Body Leakage Current | V _{GS} =±20V, V _{DS} =0V | | | ±100 | nA |
| VGS(th) | Gate Threshold Voltage | V _{DS} =V _{GS} , ID=250μA | 2.0 | 2.9 | 4.0 | V |
| GFS | Forward Transconductance | V _{DS} =5V, I _D =15A | | 33 | | S |
| RDS(ON) | Drain-Source On-State Resistance | V _{GS} =10V, I _D =40A | | 4.8 | 5.8 | mΩ |
| Ciss | Input Capacitance | V _{DS} =25V, V _{GS} =0V, f=1.0MHz | | 4200 | | pF |
| Coss | Output Capacitance | | | 2867 | | pF |
| Crss | Reverse Transfer Capacitance | | | 215 | | pF |
| td(on) | Turn-on Delay Time | V _{GS} =10V, V _{DS} =75V, RL=1.07Ω, RGEN=3Ω | | 18 | | nS |
| tr | Turn-on Rise Time | | | 22 | | nS |
| td(off) | Turn-Off Delay Time | | | 35 | | nS |
| tr | Turn-Off Fall Time | | | 10 | | nS |
| Qg | Total Gate Charge | V _{GS} =10V, V _{DS} =75V, I _D =70A | | 65 | | nC |
| Qgs | Gate-Source Charge | | | 20 | | nC |
| Qgd | Gate-Drain Charge | | | 19 | | nC |
| ISD | Source-Drain Current (Body Diode) | | | | 240 | A |
| VSD | Forward on Voltage (Note 3) | V _{GS} =0V, I _S =20A | | | 1.2 | V |
| trr | Reverse Recovery Time | I _F =20A, dI/dt=500A/μs | | 101 | | ns |
| Qrr | Reverse Recovery Charge | I _F =20A, dI/dt=500A/μs | | 1,240 | | nC |

Notes:

- 1、The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.
- 2、The data tested by pulsed , pulse width ≤ 300μs , duty cycle ≤ 2%
- 3、The EAS data shows Max. rating . The test condition is V_{DD}=50V, V_{GS}=10V, L=0.5mH, I_{AS}=64A
- 4、The power dissipation is limited by 150°C junction temperature
- 5、The data is theoretically the same as I_D and I_{DM} , in real applications , should be limited by total power dissipation.

Typical Characteristics

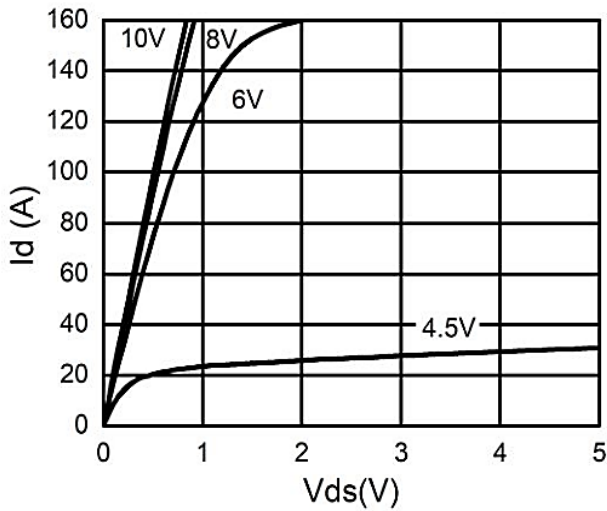


Figure 1. Output Characteristics

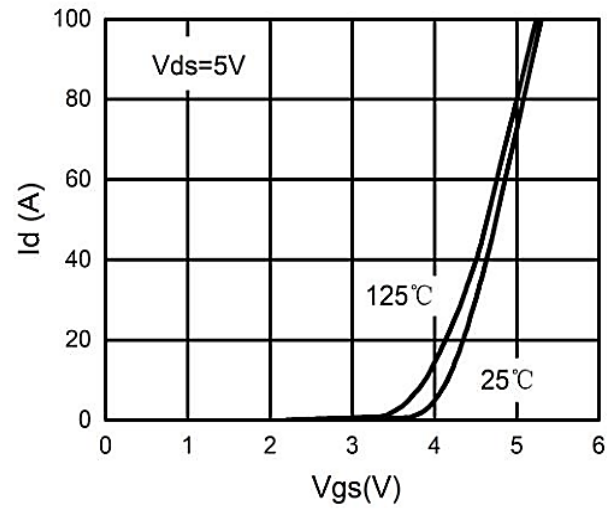


Figure 2. Transfer Characteristics

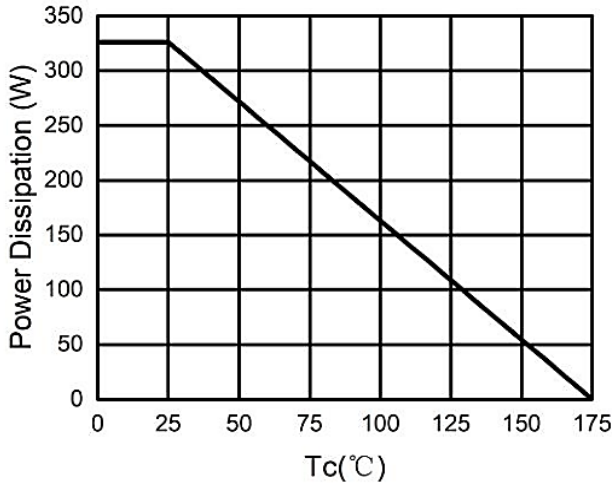


Figure 3. Power Dissipation

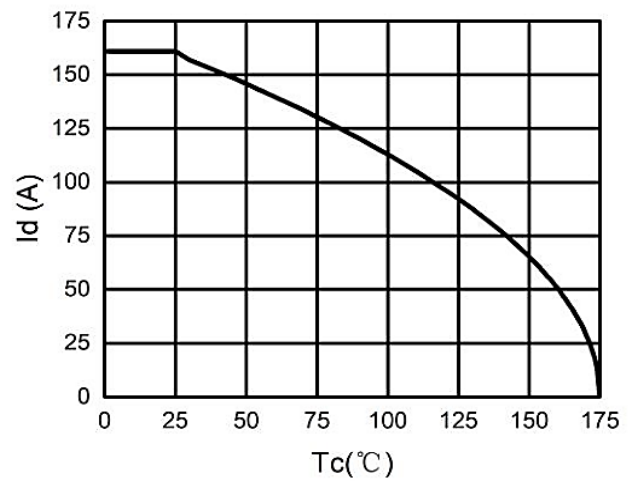


Figure 4. Drain Current

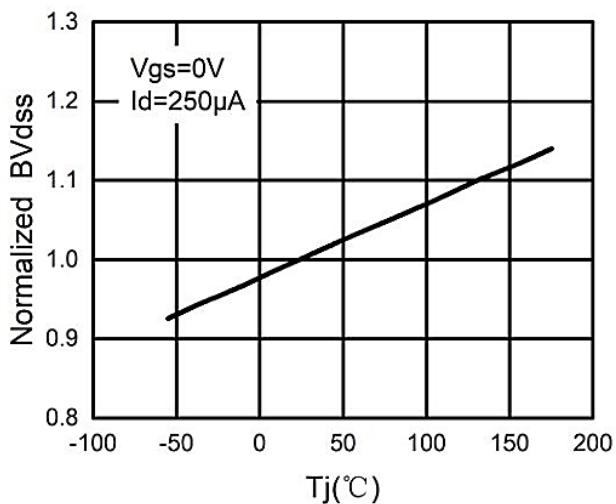


Figure 5. BVDSS vs Junction Temperature

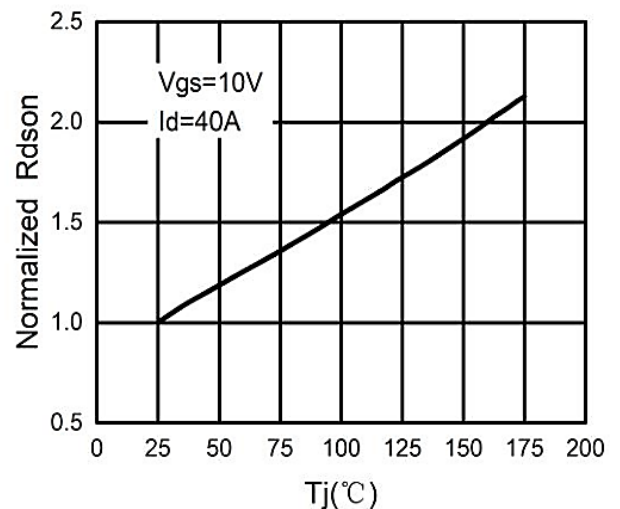


Figure 6. RDS(ON) vs Junction Temperature

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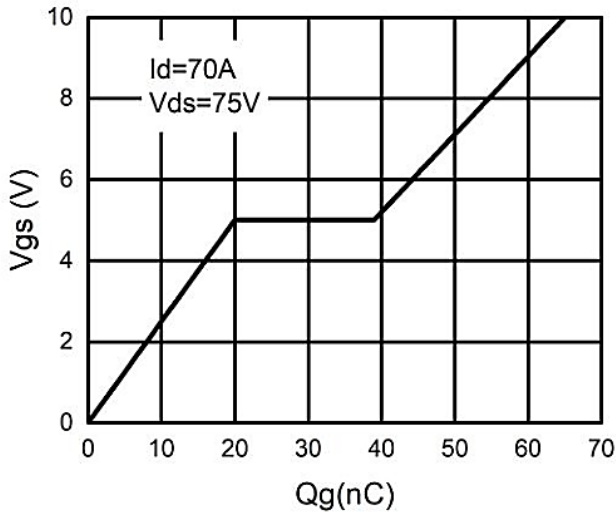


Figure 7. Gate Charge Waveforms

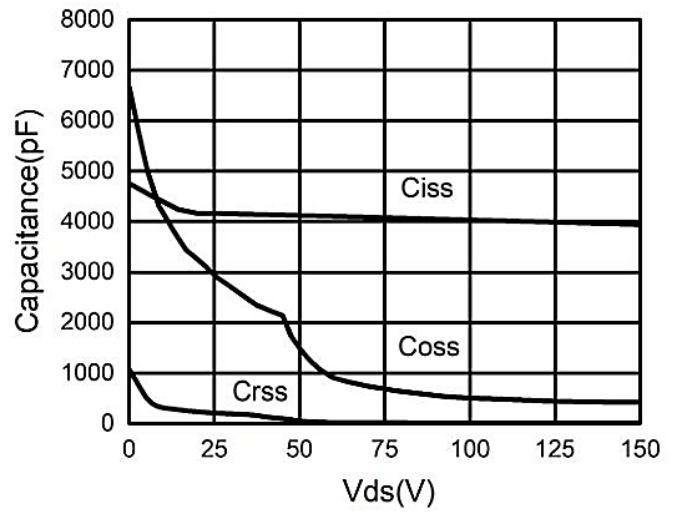


Figure 8. Capacitance

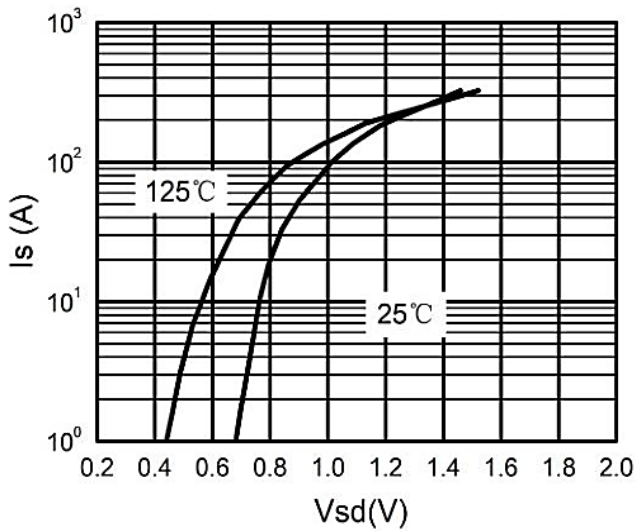


Figure 9. Body-Diode Characteristics

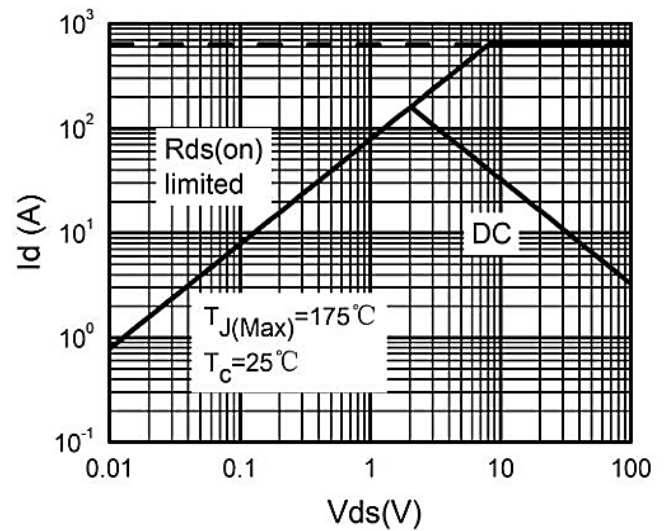


Figure 10. Maximum Safe Operating Area

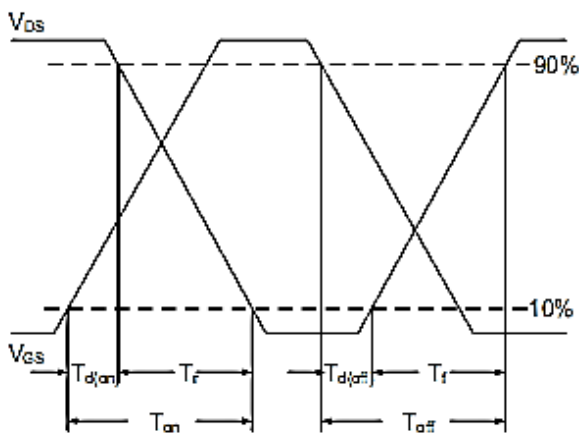


Figure 11. Switching Time Waveform

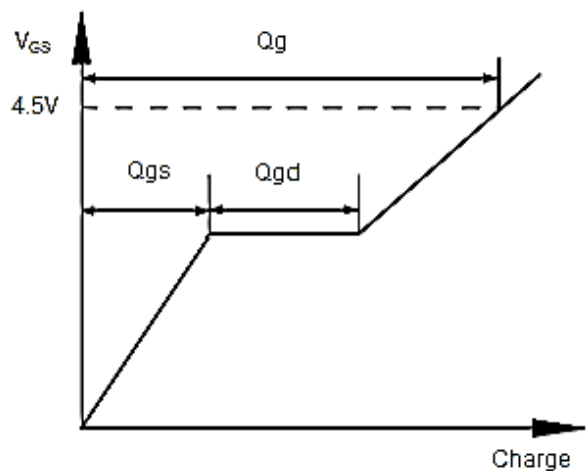
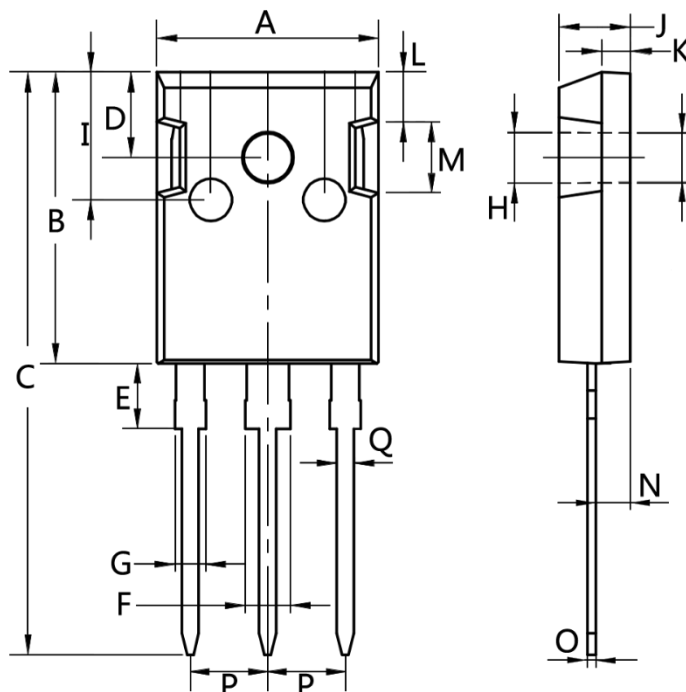


Figure 12. Gate Charge Waveform

Package Mechanical Data-TO-247-3L



| Dim. | Min. | Max. |
|------|----------|------|
| A | 15.0 | 16.0 |
| B | 20.0 | 21.0 |
| C | 41.0 | 42.0 |
| D | 5.0 | 6.0 |
| E | 4.0 | 5.0 |
| F | 2.5 | 3.5 |
| G | 1.75 | 2.5 |
| H | 3.0 | 3.5 |
| I | 8.0 | 10.0 |
| J | 4.9 | 5.1 |
| K | 1.9 | 2.1 |
| L | 3.5 | 4.0 |
| M | 4.75 | 5.25 |
| N | 2.0 | 3.0 |
| O | 0.55 | 0.75 |
| P | Typ 5.08 | |
| Q | 1.2 | 1.3 |

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